國立交通大學

工學院半導體材料與製程設備學程

碩士論文

錫鉛覆晶銲錫中金屬墊層電遷移與熱遷 移行為之研究

Effect of UBM structure on Electromigration and thermomigration behavior in flip chip SnPb solder joints

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A Thesis

Submitted to Degree Program of Semiconductor Material and Process Equipment College of Engineering

National Chiao Tung University in Partial Fulfillment of the Requirements for the Degree of Master

in

Program of Semiconductor Material and Processing Equipment

July 2011

Hsinchu, Taiwan, Republic of China

中華民國一百年七月